Hybrid 8j99 Traveler

August 14, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J99 has die: 038-030 043-018 101-048 232-128 099-037 099-038 099-039 099-040

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j99 classification info. Created 09:46:28 06/05/00

Hybrid 8j99 quality: fair
Chip classification: good good fair fair fair fair good fair
Bad channels (chip-channel): 2-22 3-75 5-68
Bad cells: none
Random bad capacitors (chip-cell-channel): 2-44-21 2-44-23 4-25-108
   7-6-21
Channels at pedestal needed for DCMS: 35.6 34.5 32.7 32.6 34.6 35.5 35.6 36.6
```

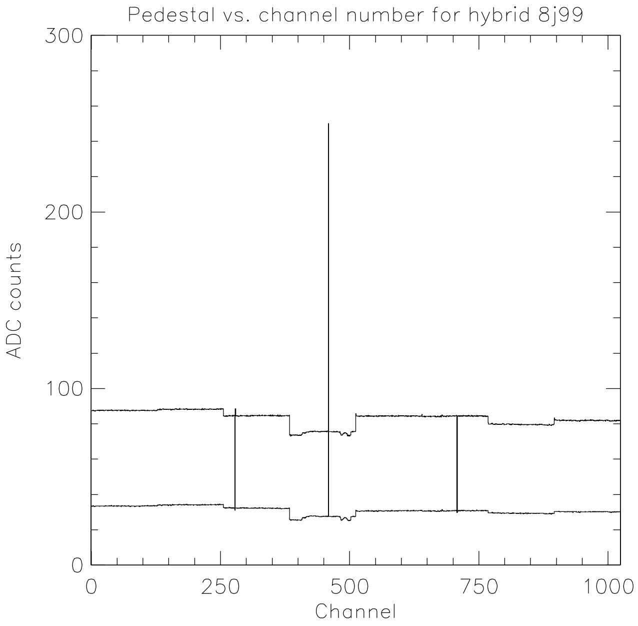
4 Comments

HV tested.

5 Pedestal

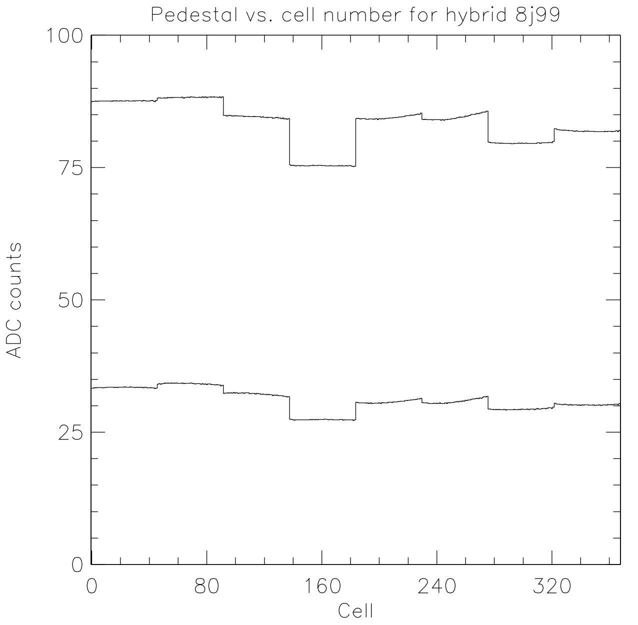
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

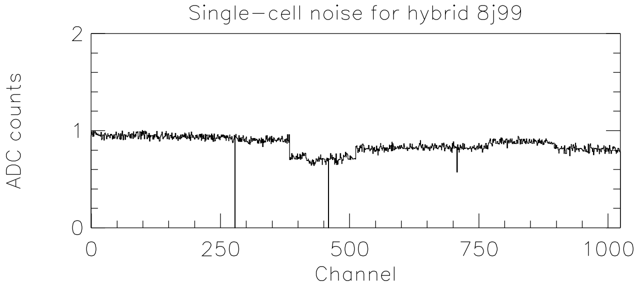
Pedestal vs. Pipeline Cell ID

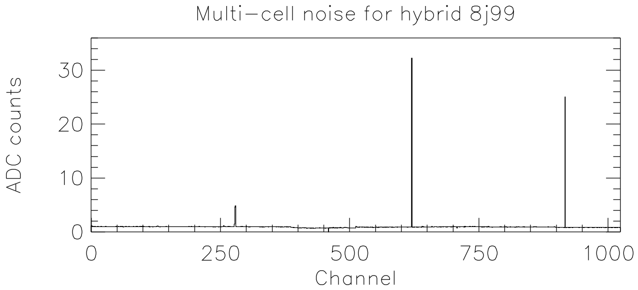


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

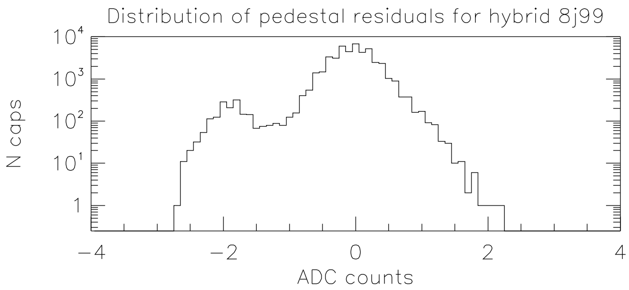
RMS Noise

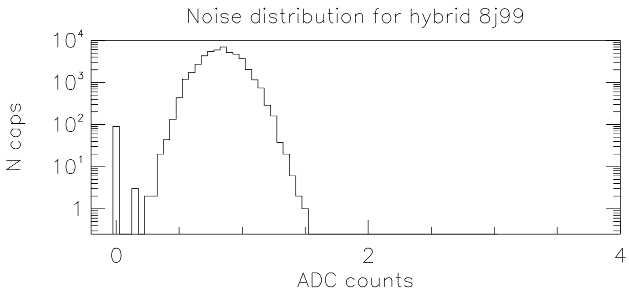




The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in